Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, I²S, POR, PWM, WDT
Number of I/O	37
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	32K x 8
Voltage - Supply (Vcc/Vdd)	1.65V ~ 3.6V
Data Converters	A/D 13x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f098cct7

List of tables

Figure 6. LQFP64 package pinout

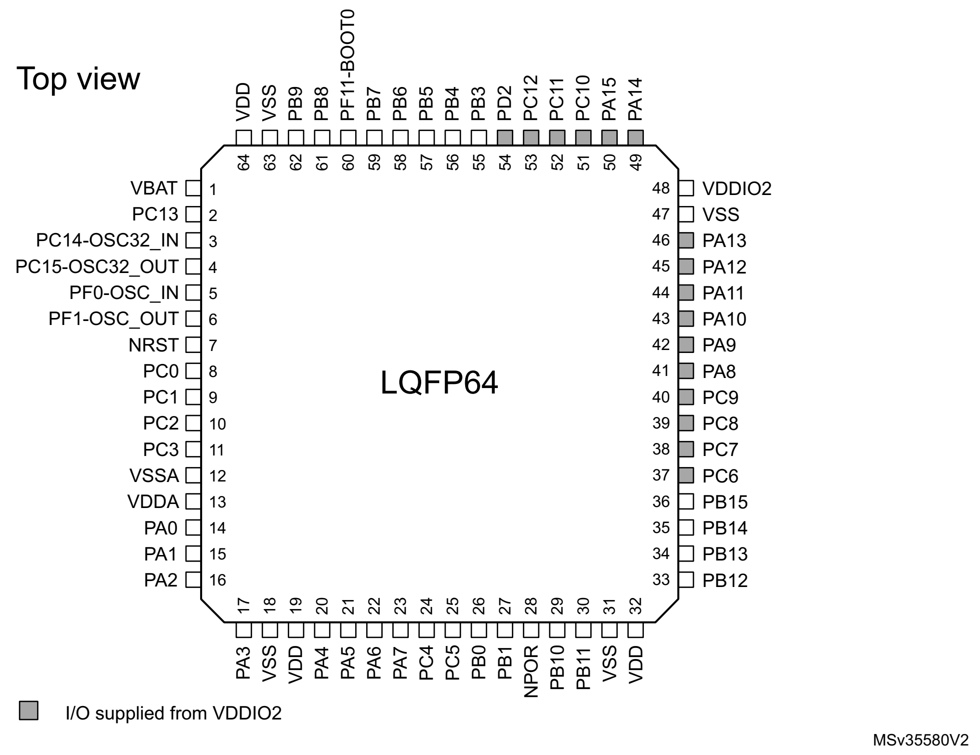


Table 12. STM32F098CC/RC/VC pin definitions (continued)

Pin numbers						Pin name (function upon reset)	Pin type	I/O structure	Notes	Pin functions	
UFBGA100	LQFP100	UFBGA64	LQFP64	WLCSP64	LQFP48/UFQFPN48					Alternate functions	Additional functions
D3	99	D4	63	A7	47	VSS	S	-		Ground	
C4	100	E4	64	A8	48	VDD	S	-		Digital power supply	

1. PC13, PC14 and PC15 are supplied through the power switch. Since the switch only sinks a limited amount of current (3 mA), the use of GPIOs PC13 to PC15 in output mode is limited:
   - The speed should not exceed 2 MHz with a maximum load of 30 pF.
   - These GPIOs must not be used as current sources (e.g. to drive an LED).
2. After the first RTC domain power-up, PC13, PC14 and PC15 operate as GPIOs. Their function then depends on the content of the RTC registers which are not reset by the system reset. For details on how to manage these GPIOs, refer to the RTC domain and RTC register descriptions in the reference manual.
3. This pin is powered by VDDA.
4. PC6, PC7, PC8, PC9, PA8, PA9, PA10, PA11, PA12, PA13, PF6, PA14, PA15, PC10, PC11, PC12, PD0, PD1 and PD2 I/Os are supplied by VDDIO2
5. After reset, these pins are configured as SWDIO and SWCLK alternate functions, and the internal pull-up on the SWDIO pin and the internal pull-down on the SWCLK pin are activated.

Table 14. Alternate functions selected through GPIOB_AFR registers for port B

Pin name	AF0	AF1	AF2	AF3	AF4	AF5
PB0	EVENTOUT	TIM3_CH3	TIM1_CH2N	TSC_G3_IO2	USART3_CK	-
PB1	TIM14_CH1	TIM3_CH4	TIM1_CH3N	TSC_G3_IO3	USART3_RTS	-
PB3	SPI1_SCK, I2S1_CK	EVENTOUT	TIM2_CH2	TSC_G5_IO1		-
PB4	SPI1_MISO, I2S1_MCK	TIM3_CH1	EVENTOUT	TSC_G5_IO2		TIM17_BKIN
PB5	SPI1_MOSI, I2S1_SD	TIM3_CH2	TIM16_BKIN	I2C1_SMBA		-
PB6	USART1_TX	I2C1_SCL	TIM16_CH1N	TSC_G5_IO3	-	-
PB7	USART1_RX	I2C1_SDA	TIM17_CH1N	TSC_G5_IO4	USART4_CTS	-
PB8	CEC	I2C1_SCL	TIM16_CH1	TSC_SYNC	CAN_RX	-
PB9	IR_OUT	I2C1_SDA	TIM17_CH1	EVENTOUT	CAN_TX	SPI2_NSS, I2S2_WS
PB10	CEC	I2C2_SCL	TIM2_CH3	TSC_SYNC	USART3_TX	SPI2_SCK, I2S2_CK
PB11	EVENTOUT	I2C2_SDA	TIM2_CH4	TSC_G6_IO1	USART3_RX	-
PB12	SPI2_NSS, I2S2_WS	EVENTOUT	TIM1_BKIN	TSC_G6_IO2	USART3_CK	TIM15_BKIN
PB13	SPI2_SCK, I2S2_CK	-	TIM1_CH1N	TSC_G6_IO3	USART3_CTS	I2C2_SCL
PB14	SPI2_MISO, I2S2_MCK	TIM15_CH1	TIM1_CH2N	TSC_G6_IO4	USART3_RTS	I2C2_SDA
PB15	SPI2_MOSI, I2S2_SD	TIM15_CH2	TIM1_CH3N	TIM15_CH1N	-	-

Table 15. Alternate functions selected through GPIOC_AFR registers for port C

Pin name	AF0	AF1	AF2
PC0	EVENTOUT	USART7_TX	USART6_TX
PC1	EVENTOUT	USART7_RX	USART6_RX
PC2	EVENTOUT	SPI2_MISO, I2S2_MCK	USART8_TX
PC3	EVENTOUT	SPI2_MOSI, I2S2_SD	USART8_RX
PC4	EVENTOUT	USART3_TX	-
PC5	TSC_G3_IO1	USART3_RX	-
PC6	TIM3_CH1	USART7_TX	-
PC7	TIM3_CH2	USART7_RX	-
PC8	TIM3_CH3	USART8_TX	-
PC9	TIM3_CH4	USART8_RX	-
PC10	USART4_TX	USART3_TX	-
PC11	USART4_RX	USART3_RX	-
PC12	USART4_CK	USART3_CK	USART5_TX
PC13	-	-	-
PC14	-	-	-
PC15	-	-	-

Table 16. Alternate functions selected through GPIOD_AFR registers for port D

Pin name	AF0	AF1	AF2
PD0	CAN_RX	SPI2_NSS, I2S2_WS	-
PD1	CAN_TX	SPI2_SCK, I2S2_CK	-
PD2	TIM3_ETR	USART3_RTS	USART5_RX
PD3	USART2_CTS	SPI2_MISO, I2S2_MCK	-
PD4	USART2_RTS	SPI2_MOSI, I2S2_SD	-
PD5	USART2_TX	-	-
PD6	USART2_RX	-	-
PD7	USART2_CK	-	-
PD8	USART3_TX	-	-
PD9	USART3_RX	-	-
PD10	USART3_CK	-	-
PD11	USART3_CTS	-	-
PD12	USART3_RTS	TSC_G8_IO1	USART8_CK_RTS
PD13	USART8_TX	TSC_G8_IO2	-
PD14	USART8_RX	TSC_G8_IO3	-
PD15	CRS_SYNC	TSC_G8_IO4	USART7_CK_RTS

Table 26. Typical and maximum current consumption from V_{DD} supply at V_{DD} = 1.8 V

Symbol	Parameter	Conditions	f_{HCLK}	All peripherals enabled				All peripherals disabled				Unit
				Typ	Max @ T_A(1)			Typ	Max @ T_A(1)			
					25 °C	85 °C	105 °C		25 °C	85 °C	105 °C	
I_{DD}	Supply current in Run mode, code executing from Flash memory	HSI48	48 MHz	26.2	28.0	28.8	28.9	14.2	15.1	15.2	15.3	mA
		HSE bypass, PLL on	48 MHz	26.1	27.9	28.7	28.8	14.1	15.0	15.1	15.3	
			32 MHz	17.7	18.9	19.4	19.5	9.6	10.2	10.3	10.4	
			24 MHz	13.8	14.6	14.9	15.0	7.9	8.2	8.4	8.6	
		HSE bypass, PLL off	8 MHz	4.7	5.0	5.1	5.3	2.7	2.9	2.9	2.9	
			1 MHz	0.8	0.9	1.0	1.1	0.6	0.7	0.8	0.8	
		HSI clock, PLL on	48 MHz	26.1	27.9	28.7	28.9	14.1	15.0	15.2	15.3	
			32 MHz	17.8	19.0	19.4	19.5	9.7	10.2	10.4	10.4	
			24 MHz	13.9	14.7	15.0	15.1	8.0	8.3	8.5	8.7	
		HSI clock, PLL off	8 MHz	4.8	5.1	5.1	5.4	2.7	2.9	2.9	2.9	
	Supply current in Run mode, code executing from RAM	HSI48	48 MHz	25.7	27.6	28.2	28.5	13.6	14.6	14.7	14.9	
		HSE bypass, PLL on	48 MHz	25.5	27.4	28.1	28.3	13.5	14.5	14.7	14.8	
			32 MHz	17.2	18.4	18.9	19.0	9.1	9.7	9.9	9.9	
			24 MHz	13.1	14.0	14.3	14.4	7.1	7.5	7.7	7.8	
		HSE bypass, PLL off	8 MHz	4.2	4.6	4.7	4.8	2.3	2.5	2.5	2.6	
			1 MHz	0.5	0.7	0.7	0.7	0.3	0.4	0.4	0.5	
		HSI clock, PLL on	48 MHz	25.6	27.5	28.2	28.4	13.6	14.5	14.7	14.8	
			32 MHz	17.3	18.5	18.9	19.0	9.1	9.8	9.9	10.0	
			24 MHz	13.2	14.1	14.4	14.4	7.2	7.6	7.8	7.9	
		HSI clock, PLL off	8 MHz	4.4	4.7	4.9	4.9	2.3	2.6	2.6	2.6	
	Supply current in Sleep mode	HSI48	48 MHz	16.5	17.7	18.2	18.3	3.1	3.4	3.5	3.6	mA
		HSE bypass, PLL on	48 MHz	16.4	17.6	18.0	18.1	3.1	3.3	3.4	3.5	
			32 MHz	11.1	11.9	12.2	12.3	2.1	2.3	2.4	2.5	
			24 MHz	8.4	9.1	9.3	9.4	1.6	1.8	1.9	2.0	
		HSE bypass, PLL off	8 MHz	2.8	3.0	3.1	3.4	0.5	0.7	0.7	0.8	
			1 MHz	0.4	0.5	0.5	0.6	0.2	0.3	0.3	0.4	
		HSI clock, PLL on	48 MHz	16.4	17.7	18.1	18.2	3.1	3.3	3.4	3.5	
			32 MHz	11.2	12.0	12.2	12.3	2.2	2.4	2.5	2.6	
			24 MHz	8.5	9.1	9.3	9.4	1.7	1.8	1.9	2.0	
		HSI clock, PLL off	8 MHz	2.8	3.1	3.1	3.5	0.6	0.7	0.7	0.8	

Table 29. Typical and maximum current consumption from the V_{BAT} supply

Symbol	Parameter	Conditions	Typ @ V_{BAT}						Max[1]			Unit
			1.65 V	1.8 V	2.4 V	2.7 V	3.3 V	3.6 V	T_A = 25 °C	T_A = 85 °C	T_A = 105 °C	
I_{DD_VBAT}	RTC domain supply current	LSE & RTC ON; “Xtal mode”: lower driving capability; LSEDRV[1:0] = '00'	0.5	0.5	0.6	0.7	0.9	1.0	1.0	1.3	1.8	µA
		LSE & RTC ON; “Xtal mode” higher driving capability; LSEDRV[1:0] = '11'	0.8	0.8	0.9	1.0	1.2	1.3	1.4	1.7	2.2	

1. Data based on characterization results, not tested in production.

Typical current consumption

The MCU is placed under the following conditions:

- $V_{DD} = V_{DDA}$ = 1.8 V
- All I/O pins are in analog input configuration
- The Flash memory access time is adjusted to f_{HCLK} frequency:
  - 0 wait state and Prefetch OFF from 0 to 24 MHz
  - 1 wait state and Prefetch ON above 24 MHz
- When the peripherals are enabled, $f_{PCLK} = f_{HCLK}$
- PLL is used for frequencies greater than 8 MHz
- AHB prescaler of 2, 4, 8 and 16 is used for the frequencies 4 MHz, 2 MHz, 1 MHz and 500 kHz respectively

Table 44. Flash memory endurance and data retention

Symbol	Parameter	Conditions	Min[1]	Unit
N_{END}	Endurance	T_A = –40 to +105 °C	10	kcycle
t_{RET}	Data retention	1 kcycle[2] at T_A = 85 °C	30	Year
		1 kcycle[2] at T_A = 105 °C	10	
		10 kcycle[2] at T_A = 55 °C	20	

1. Data based on characterization results, not tested in production.
2. Cycling performed over the whole temperature range.

6.3.10 EMC characteristics

Susceptibility tests are performed on a sample basis during device characterization.

Functional EMS (electromagnetic susceptibility)

While a simple application is executed on the device (toggling 2 LEDs through I/O ports). the device is stressed by two electromagnetic events until a failure occurs. The failure is indicated by the LEDs:

- **Electrostatic discharge (ESD)** (positive and negative) is applied to all device pins until a functional disturbance occurs. This test is compliant with the IEC 61000-4-2 standard.
- **FTB**: A Burst of Fast Transient voltage (positive and negative) is applied to V_{DD} and V_{SS} through a 100 pF capacitor, until a functional disturbance occurs. This test is compliant with the IEC 61000-4-4 standard.

A device reset allows normal operations to be resumed.

The test results are given in *Table 45*. They are based on the EMS levels and classes defined in application note AN1709.

Table 45. EMS characteristics

Symbol	Parameter	Conditions	Level/ Class
V_{FESD}	Voltage limits to be applied on any I/O pin to induce a functional disturbance	V_{DD} = 1.8 V, LQFP100, T_A = +25 °C, f_{HCLK} = 48 MHz, conforming to IEC 61000-4-2	2B
V_{EFTB}	Fast transient voltage burst limits to be applied through 100 pF on V_{DD} and V_{SS} pins to induce a functional disturbance	V_{DD} = 1.8 V, LQFP100, T_A = +25°C, f_{HCLK} = 48 MHz, conforming to IEC 61000-4-4	4B

Designing hardened software to avoid noise problems

EMC characterization and optimization are performed at component level with a typical application environment and simplified MCU software. It should be noted that good EMC performance is highly dependent on the user application and the software in particular.

Therefore it is recommended that the user applies EMC software optimization and prequalification tests in relation with the EMC level requested for his application.

Software recommendations

The software flowchart must include the management of runaway conditions such as:

- Corrupted program counter
- Unexpected reset
- Critical Data corruption (for example control registers)

Prequalification trials

Most of the common failures (unexpected reset and program counter corruption) can be reproduced by manually forcing a low state on the NRST pin or the Oscillator pins for 1 second.

To complete these trials, ESD stress can be applied directly on the device, over the range of specification values. When unexpected behavior is detected, the software can be hardened to prevent unrecoverable errors occurring (see application note AN1015).

Electromagnetic Interference (EMI)

The electromagnetic field emitted by the device are monitored while a simple application is executed (toggling 2 LEDs through the I/O ports). This emission test is compliant with IEC 61967-2 standard which specifies the test board and the pin loading.

Table 46. EMI characteristics

Symbol	Parameter	Conditions	Monitored frequency band	Max vs. [f_{HSE}/f_{HCLK}]	Unit
				8/48 MHz	
S_{EMI}	Peak level	V_{DD} = 1.8 V, T_A = 25 °C, LQFP100 package compliant with IEC 61967-2	0.1 to 30 MHz	3	dBµV
			30 to 130 MHz	23	
			130 MHz to 1 GHz	15	
			EMI Level	4	-

6.3.11 Electrical sensitivity characteristics

Based on three different tests (ESD, LU) using specific measurement methods, the device is stressed in order to determine its performance in terms of electrical sensitivity.

Electrostatic discharge (ESD)

Electrostatic discharges (a positive then a negative pulse separated by 1 second) are applied to the pins of each sample according to each pin combination. The sample size depends on the number of supply pins in the device (3 parts × (n+1) supply pins). This test conforms to the JESD22-A114/C101 standard.

Table 55. ADC characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$W_{LATENCY}$[2][4]	ADC_DR register ready latency	ADC clock = HSI14	1.5 ADC cycles + 2 f_{PCLK} cycles	-	1.5 ADC cycles + 3 f_{PCLK} cycles	-
		ADC clock = PCLK/2	-	4.5	-	f_{PCLK} cycle
		ADC clock = PCLK/4	-	8.5	-	f_{PCLK} cycle
t_{latr}[2]	Trigger conversion latency	$f_{ADC} = f_{PCLK}/2 = 14$ MHz	0.196			µs
		$f_{ADC} = f_{PCLK}/2$	5.5			$1/f_{PCLK}$
		$f_{ADC} = f_{PCLK}/4 = 12$ MHz	0.219			µs
		$f_{ADC} = f_{PCLK}/4$	10.5			$1/f_{PCLK}$
		$f_{ADC} = f_{HSI14} = 14$ MHz	0.179	-	0.250	µs
$Jitter_{ADC}$	ADC jitter on trigger conversion	$f_{ADC} = f_{HSI14}$	-	1	-	$1/f_{HSI14}$
t_S[2]	Sampling time	$f_{ADC} = 14$ MHz	0.107	-	17.1	µs
		-	1.5	-	239.5	$1/f_{ADC}$
t_{STAB}[2]	Stabilization time	-	14			$1/f_{ADC}$
t_{CONV}[2]	Total conversion time (including sampling time)	$f_{ADC} = 14$ MHz, 12-bit resolution	1	-	18	µs
		12-bit resolution	14 to 252 (t_S for sampling +12.5 for successive approximation)			$1/f_{ADC}$

1. During conversion of the sampled value (12.5 x ADC clock period), an additional consumption of 100 µA on I_{DDA} and 60 µA on I_{DD} should be taken into account.
2. Guaranteed by design, not tested in production.
3. Specified value includes only ADC timing. It does not include the latency of the register access.
4. This parameter specify latency for transfer of the conversion result to the ADC_DR register. EOC flag is set at this time.

Equation 1: R_{AIN} max formula

$$R_{AIN} < \frac{T_S}{f_{ADC} \times C_{ADC} \times \ln(2^{N+2})} - R_{ADC}$$

The formula above (*Equation 1*) is used to determine the maximum external impedance allowed for an error below 1/4 of LSB. Here N = 12 (from 12-bit resolution).

Table 56. R_{AIN} max for f_{ADC} = 14 MHz

T_s (cycles)	t_S (µs)	R_{AIN} max (kΩ)[1]
1.5	0.11	0.4
7.5	0.54	5.9
13.5	0.96	11.4

Table 56. R_{AIN} max for f_{ADC} = 14 MHz (continued)

T_S (cycles)	t_S (µs)	R_{AIN} max (kΩ)[1]
28.5	2.04	25.2
41.5	2.96	37.2
55.5	3.96	50
71.5	5.11	NA
239.5	17.1	NA

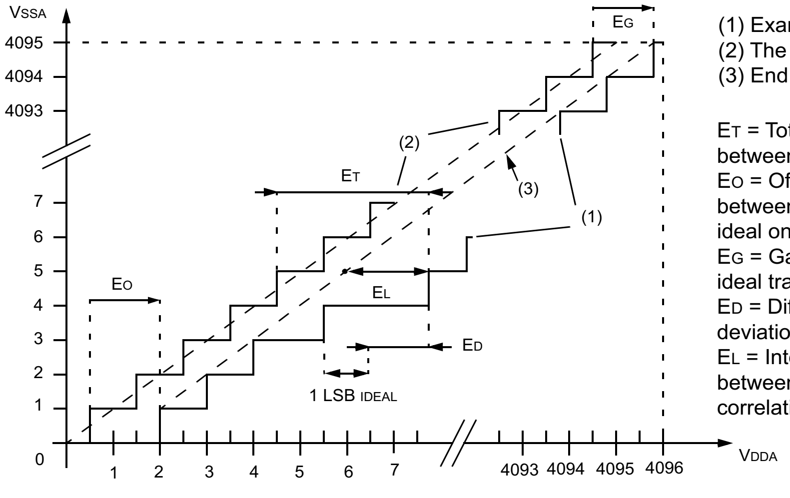
1. Guaranteed by design, not tested in production.

Table 57. ADC accuracy(1)(2)(3)

Symbol	Parameter	Test conditions	Typ	Max(4)	Unit
ET	Total unadjusted error	f_{PCLK} = 48 MHz, f_{ADC} = 14 MHz, R_{AIN} < 10 kΩ V_{DDA} = 3 V to 3.6 V T_A = 25 °C	±1.3	±2	LSB
EO	Offset error		±1	±1.5	
EG	Gain error		±0.5	±1.5	
ED	Differential linearity error		±0.7	±1	
EL	Integral linearity error		±0.8	±1.5	
ET	Total unadjusted error	f_{PCLK} = 48 MHz, f_{ADC} = 14 MHz, R_{AIN} < 10 kΩ V_{DDA} = 2.7 V to 3.6 V T_A = - 40 to 105 °C	±3.3	±4	LSB
EO	Offset error		±1.9	±2.8	
EG	Gain error		±2.8	±3	
ED	Differential linearity error		±0.7	±1.3	
EL	Integral linearity error		±1.2	±1.7	
ET	Total unadjusted error	f_{PCLK} = 48 MHz, f_{ADC} = 14 MHz, R_{AIN} < 10 kΩ V_{DDA} = 2.4 V to 3.6 V T_A = 25 °C	±3.3	±4	LSB
EO	Offset error		±1.9	±2.8	
EG	Gain error		±2.8	±3	
ED	Differential linearity error		±0.7	±1.3	
EL	Integral linearity error		±1.2	±1.7	

1. ADC DC accuracy values are measured after internal calibration.
2. ADC Accuracy vs. Negative Injection Current: Injecting negative current on any of the standard (non-robust) analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to standard analog pins which may potentially inject negative current.
   Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in *Section 6.3.13* does not affect the ADC accuracy.
3. Better performance may be achieved in restricted V_{DDA}, frequency and temperature ranges.
4. Data based on characterization results, not tested in production.

Figure 26. ADC accuracy characteristics



(1) Example of an actual transfer curve
(2) The ideal transfer curve
(3) End point correlation line

E_T = Total Unajusted Error: maximum deviation between the actual and ideal transfer curves.
E_O = Offset Error: maximum deviation between the first actual transition and the first ideal one.
E_G = Gain Error: deviation between the last ideal transition and the last actual one.
E_D = Differential Linearity Error: maximum deviation between actual steps and the ideal ones.
E_L = Integral Linearity Error: maximum deviation between any actual transition and the end point correlation line.

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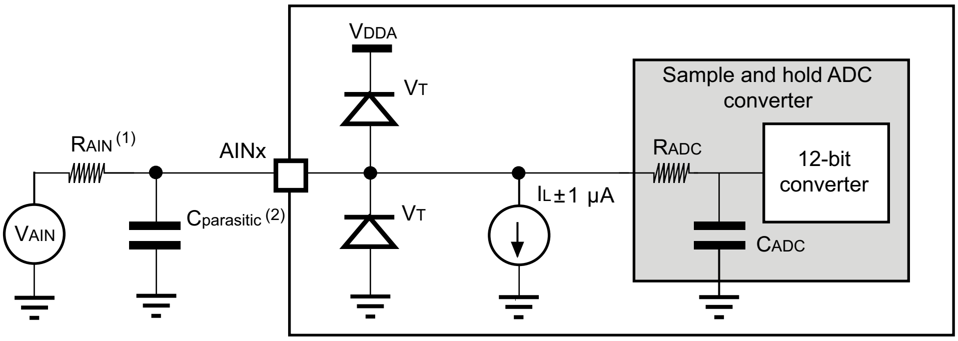
Figure 27. Typical connection diagram using the ADC



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1. Refer to *Table 55: ADC characteristics* for the values of R_{AIN}, R_{ADC} and C_{ADC}.
2. $C_{parasitic}$ represents the capacitance of the PCB (dependent on soldering and PCB layout quality) plus the pad capacitance (roughly 7 pF). A high $C_{parasitic}$ value will downgrade conversion accuracy. To remedy this, f_{ADC} should be reduced.

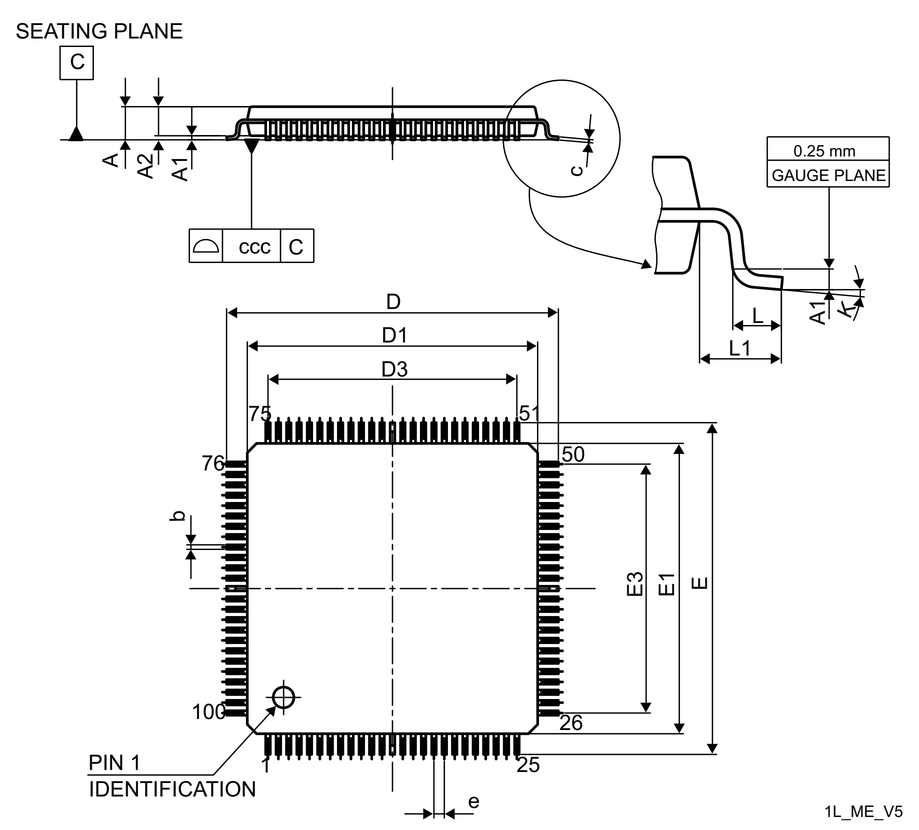
General PCB design guidelines

Power supply decoupling should be performed as shown in *Figure 13: Power supply scheme*. The 10 nF capacitor should be ceramic (good quality) and it should be placed as close as possible to the chip.

7.2 LQFP100 package information

LQFP100 is a100-pin, 14 x 14 mm low-profile quad flat package.

Figure 36. LQFP100 package outline



1. Drawing is not to scale.

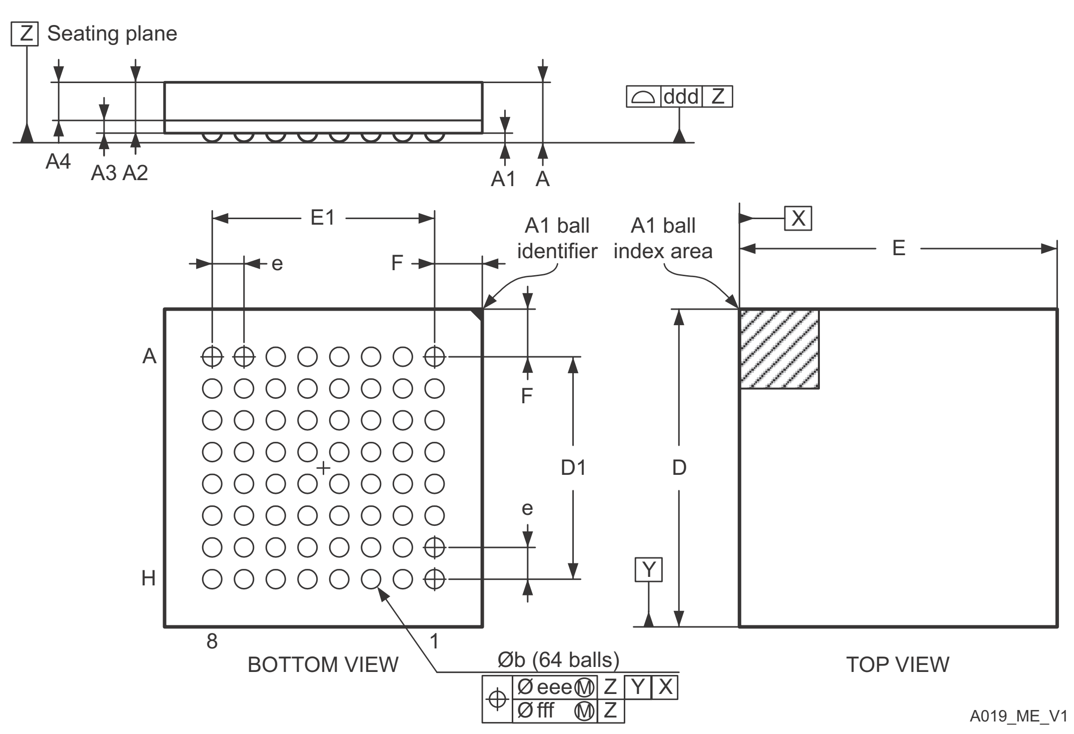
Table 70. LQPF100 package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	15.800	16.000	16.200	0.6220	0.6299	0.6378
D1	13.800	14.000	14.200	0.5433	0.5512	0.5591
D3	-	12.000	-	-	0.4724	-
E	15.800	16.000	16.200	0.6220	0.6299	0.6378

7.3 UFBGA64 package information

UFBGA64 is a 64-ball, 5 x 5 mm, 0.5 mm pitch ultra-fine-profile ball grid array package.

Figure 39. UFBGA64 package outline



1. Drawing is not to scale.

Table 71. UFBGA64 package mechanical data

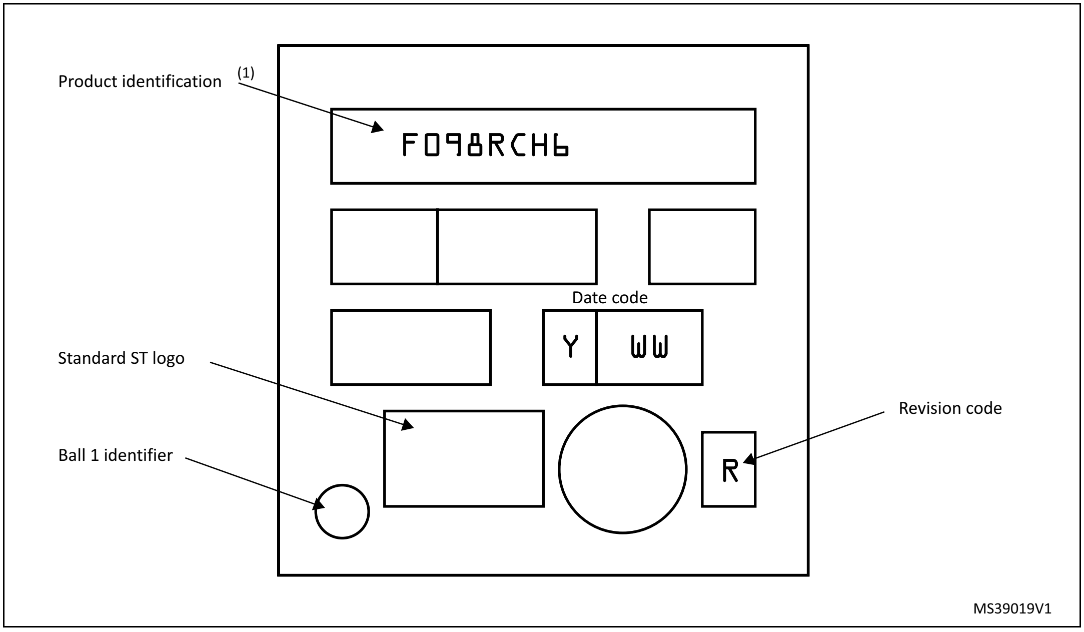
Symbol	millimeters			inches(1)		
	Min	Typ	Max	Min	Typ	Max
A	0.460	0.530	0.600	0.0181	0.0209	0.0236
A1	0.050	0.080	0.110	0.0020	0.0031	0.0043
A2	0.400	0.450	0.500	0.0157	0.0177	0.0197
A3	0.080	0.130	0.180	0.0031	0.0051	0.0071
A4	0.270	0.320	0.370	0.0106	0.0126	0.0146
b	0.170	0.280	0.330	0.0067	0.0110	0.0130
D	4.850	5.000	5.150	0.1909	0.1969	0.2028
D1	3.450	3.500	3.550	0.1358	0.1378	0.1398
E	4.850	5.000	5.150	0.1909	0.1969	0.2028
E1	3.450	3.500	3.550	0.1358	0.1378	0.1398
e	-	0.500	-	-	0.0197	-
F	0.700	0.750	0.800	0.0276	0.0295	0.0315

Device marking

The following figure gives an example of topside marking orientation versus ball A1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 41. UFBGA64 package marking example



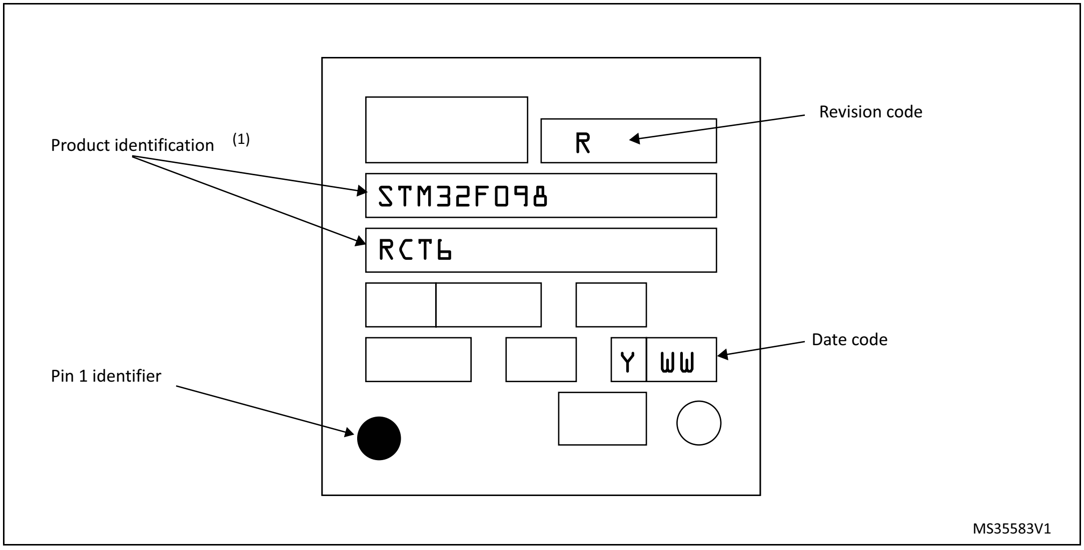
1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 47. LQFP64 package marking example



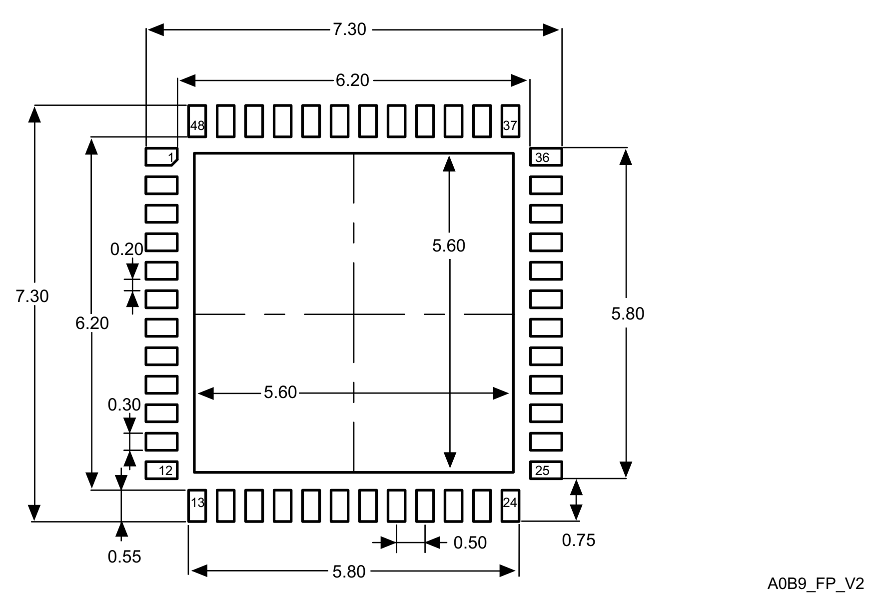
1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Table 77. UFQFPN48 package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	0.500	0.550	0.600	0.0197	0.0217	0.0236
A1	0.000	0.020	0.050	0.0000	0.0008	0.0020
D	6.900	7.000	7.100	0.2717	0.2756	0.2795
E	6.900	7.000	7.100	0.2717	0.2756	0.2795
D2	5.500	5.600	5.700	0.2165	0.2205	0.2244
E2	5.500	5.600	5.700	0.2165	0.2205	0.2244
L	0.300	0.400	0.500	0.0118	0.0157	0.0197
T	-	0.152	-	-	0.0060	-
b	0.200	0.250	0.300	0.0079	0.0098	0.0118
e	-	0.500	-	-	0.0197	-
ddd	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 52. Recommended footprint for UFQFPN48 package



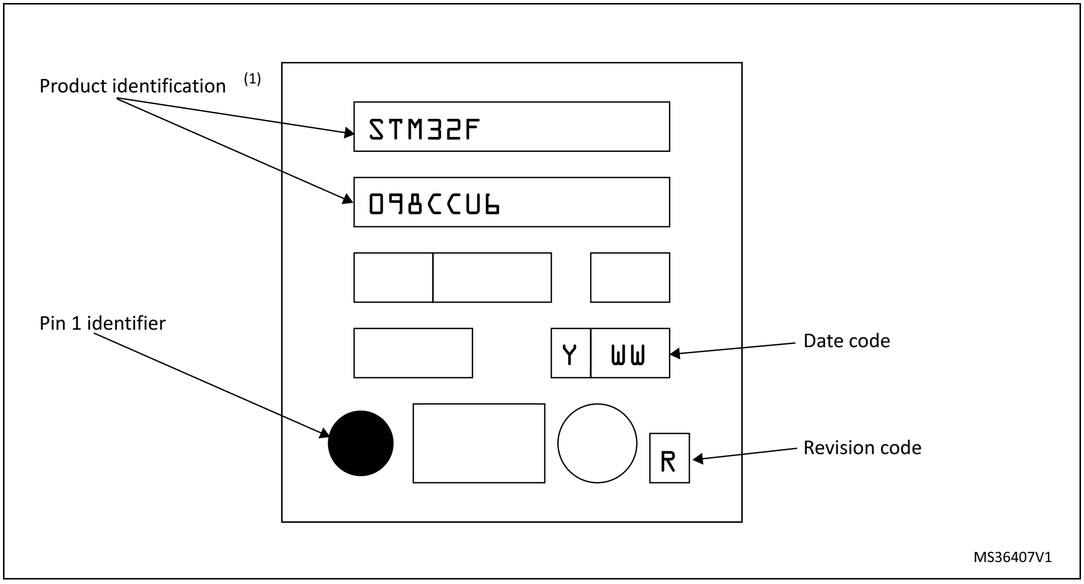
1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Other optional marking or inset/upset marks, which identify the parts throughout supply chain operations, are not indicated below.

Figure 53. UFQFPN48 package marking example



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

Table 80. Document revision history (continued)

Date	Revision	Changes
17-Dec-2015	3 (continued)	***Section 6: Electrical characteristics*:** – footnote for V_{IN} max value in *Table 20: Voltage characteristics* – footnote for V_{IN} max value in *Table 23: General operating conditions* – *Table 25: Embedded internal reference voltage*: added t_{START} parameter and removal of -40°-to-85° condition for V_{REFINT} and associated note – *Figure 18: Typical application with a 32.768 kHz crystal* - correction of OSC_IN and OSC_OUT to OSC32_IN and OSC32_OUT and f_{HSE} to f_{LSE} – *Table 47: ESD absolute maximum ratings* updated – V_{DDIOx} replaced V_{DD} in *Figure 22: TC and TTa I/O input characteristics* and *Figure 23: Five volt tolerant (FT and FTf) I/O input characteristics* – *Table 50: I/O static characteristics*- note removed – *Table 55: ADC characteristics* - updated some parameter values, test conditions and added footnotes (3) and (4) – I_{DDA} max value (DAC DC current consumption) in *Table 58: DAC characteristics* – *Table 59: Comparator characteristics* - min value added for V_{DDA} – *Table 60: TS characteristics*: removed the minimum value for t_{START} symbol and updated parameter name – R parameter typical. value in *Table 61: V_{BAT} monitoring characteristics* – *Table 62: TIMx characteristics*: removed Res_{TM} parameter line and all values put in new Typ column, $t_{COUNTER}$ substituted with t_{MAX_COUNT}, values defined as powers of two – *Table 67: I^2S characteristics* reorganized and max value added for $t_{v(SD\_ST)}$ – *Figure 32: I^2S master timing diagram (Philips protocol)* added definition of edge level references ***Section 7: Package information*:** – *Figure 33: UFBGA100 package outline* and associated *Table 68* updated – *Figure 34* and associated *Table 69* updated – *Figure 35: UFBGA100 package marking example* and associated text updated – *Figure 38: LQFP100 package marking example* and associated text updated – *Table 72: UFBGA64 recommended PCB design rules* added – *Figure 41: UFBGA64 package marking example* added ***Section 8: Part numbering*:** – added tray packing to options